

FORM PTO 1449 (modified)

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICELIST OF REFERENCES CITED BY APPLICANT(S)
(Use several sheets if necessary)

Date Submitted to PTO: October 1, 2003

ATTY DOCKET NO.
2003-1389ASERIAL NO.
NEW

10/674,430

APPLICANT
Tomiyuki MITSUNAGA et al.FILING DATE
October 1, 2003GROUP
3661

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
TN	AJ	04-326202	11/1992	JP	_____	_____	Abstract
TN	AK	2003-509700	03/2003	JP	_____	_____	Abstract
	AL						
	AM						
	AN						

OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)

	AO	
	AP	
	AQ	

EXAMINER

Jan H. H. H.

DATE CONSIDERED

02/16/2005

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of form with next communication to applicant.

FORM PTO 1449 (modified)

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICELIST OF REFERENCES CITED BY APPLICANT(S)
(Use several sheets if necessary)

Date Submitted to PTO: January 29, 2004

ATTY DOCKET NO.
2003_1389ASERIAL NO.
10/674,430APPLICANT
Tomiyuki MITSUNAGA et al.FILING DATE
October 1, 2003

GROUP

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U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
TN	AA	6,008,756	12/1999	Boerhave et al.	342	357.1	
TN	AB	4,849,827	7/1989	Hashimoto et al.	386	108	
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
TN	AJ	0 545 636	6/1993	EP	—	—	✓
TN	AK	95/28650	10/1995	WO	—	—	✓
TN	AL	25 49 791	5/1977	DE	—	—	✓
	AM						
	AN						

OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)

TN	AO	H.A. MALLIOT, "Digital Terrain Elevation Mapping System," AEROSPACE APPLICATIONS CONFERENCE, 1996. PROCEEDINGS., 1996 IEEE ASPEN, CO, U.S.A., February 3, 1996, New York, NY, pp. 91-105, XP010159095, ISBN: 0-7803-3196-6 - Figure 3.
	AP	
	AQ	

EXAMINER

Jan Kuylen

DATE CONSIDERED

02/16/2005

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